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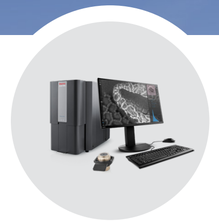
	Phenom Pure, Pro(X) G6 Desktop SEMs	Phenom XL G2 Desktop SEM	Axia ChemiSEM System	Prisma E SEM	Phenom Pharos G2 Desktop SEM	Quattro ESEM	Apreo ChemiSEM System	Verios 5 XHR SEM
Instruments								
Source type	Cerium hexaboride (CeB_6)		Tungsten (W)		Schottky field emission (FEG)			
Maximum resolution								
Sample size								
Detector type	Secondary electrons (SE)	Backscattered electrons (BSE)	Low-vacuum SE	Cathodoluminescence	Low-vacuum BSE	STEM	WetSTEM	Gaseous SED
Environmental capabilities	High vacuum			Low vacuum		Environmental		
Analytical capabilities	Elemental analysis	Particle analysis	Microstructural analysis	Correlative microscopy	Scripting	Fiber analysis	Image interpretation	

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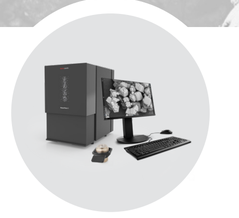
	Phenom Pure, Pro(X) G6 Desktop SEMs	Phenom XL G2 Desktop SEM	Axia ChemiSEM System	Prisma E SEM	Phenom Pharos G2 Desktop SEM	Quattro ESEM	Apreo ChemiSEM System	Verios 5 XHR SEM
Instruments								
Source type	Cerium hexaboride (CeB_6)	Tungsten (W)	Schottky field emission (FEG)					
Maximum resolution			6 nm					
Sample size	25 mm							
Detector type	Secondary electrons (SE) *	Backscattered electrons (BSE)	Low-vacuum SE	Cathodoluminescence	Low-vacuum BSE	STEM	WetSTEM	Gaseous SED
Environmental capabilities	High vacuum		Low vacuum			Environmental		
Analytical capabilities	Elemental analysis *	Particle analysis *	Microstructural analysis	Correlative microscopy *	Scripting *	Fiber analysis *	Image interpretation *	

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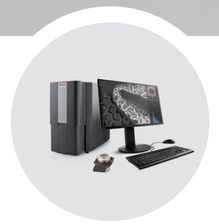
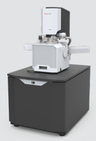
	Phenom Pure, Pro(X) G6 Desktop SEMs	Phenom XL G2 Desktop SEM	Axia ChemiSEM System	Prisma E SEM	Phenom Pharos G2 Desktop SEM	Quattro ESEM	Apreo ChemiSEM System	Verios 5 XHR SEM
Instruments								
Source type	Cerium hexaboride (CeB_6)		Tungsten (W)		Schottky field emission (FEG)			
Maximum resolution	10 nm							
Sample size						100 mm		
Detector type	Secondary electrons (SE) *	Backscattered electrons (BSE)	Low-vacuum SE	Cathodoluminescence	Low-vacuum BSE	STEM	WetSTEM	Gaseous SED
Environmental capabilities	High vacuum		Low vacuum			Environmental		
Analytical capabilities	Elemental analysis *	Particle analysis *	Microstructural analysis	Correlative microscopy *	Scripting *	Fiber analysis *	Image interpretation *	

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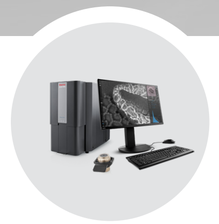
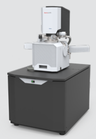
	Phenom Pure, Pro(X) G6 Desktop SEMs	Phenom XL G2 Desktop SEM	Axia ChemiSEM System	Prisma E SEM	Phenom Pharos G2 Desktop SEM	Quattro ESEM	Apreo ChemiSEM System	Verios 5 XHR SEM
Instruments								
Source type	Cerium hexaboride (CeB_6)		Tungsten (W)		Schottky field emission (FEG)			
Maximum resolution						3 nm		
Sample size								138 mm
Detector type	Secondary electrons (SE)	Backscattered electrons (BSE)	Low-vacuum SE *	Cathodoluminescence *	Low-vacuum BSE	STEM	WetSTEM	Gaseous SED
Environmental capabilities	High vacuum		Low vacuum (10-150 Pa) *			Environmental		
Analytical capabilities	Elemental analysis	Particle analysis *	Microstructural analysis	Correlative microscopy *	Scripting *	Fiber analysis *	Image interpretation *	

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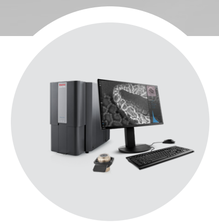
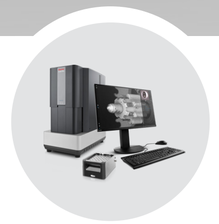
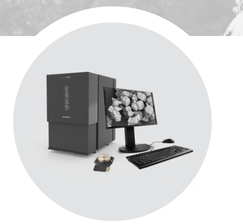
	Phenom Pure, Pro(X) G6 Desktop SEMs	Phenom XL G2 Desktop SEM	Axia ChemiSEM System	Prisma E SEM	Phenom Pharos G2 Desktop SEM	Quattro ESEM	Apreo ChemiSEM System	Verios 5 XHR SEM
							
Source type	Cerium hexaboride (CeB_6)			Tungsten (W)		Schottky field emission (FEG)		
Maximum resolution						3 nm		
Sample size							122 mm	
Detector type	Secondary electrons (SE)	Backscattered electrons (BSE)	Low-vacuum SE	Cathodoluminescence *	Low-vacuum BSE *	STEM *	WetSTEM *	Gaseous SED
Environmental capabilities	High vacuum			Low vacuum (10-130 Pa)		Environmental (130-2600 Pa)		
Analytical capabilities	Elemental analysis *	Particle analysis *	Microstructural analysis	Correlative microscopy *	Scripting *	Fiber analysis *	Image interpretation *	

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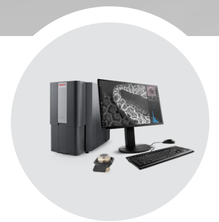
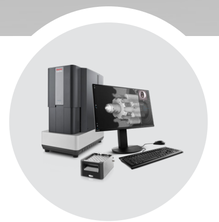
	Phenom Pure, Pro(X) G6 Desktop SEMs	Phenom XL G2 Desktop SEM	Axia ChemiSEM System	Prisma E SEM	Phenom Pharos G2 Desktop SEM	Quattro ESEM	Apreo ChemiSEM System	Verios 5 XHR SEM
Instruments								
Source type	Cerium hexaboride (CeB_6)		Tungsten (W)		Schottky field emission (FEG)			
Maximum resolution							2 nm	
Sample size	25 mm							
Detector type	Secondary electrons (SE) *	Backscattered electrons (BSE)	Low-vacuum SE	Cathodoluminescence	Low-vacuum BSE	STEM *	WetSTEM	Gaseous SED
Environmental capabilities	High vacuum		Low vacuum			Environmental		
Analytical capabilities	Elemental analysis *	Particle analysis *	Microstructural analysis	Correlative microscopy *	Scripting *	Fiber analysis *	Image interpretation *	

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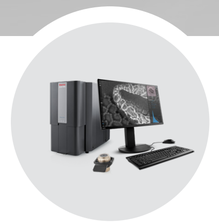
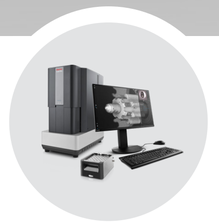
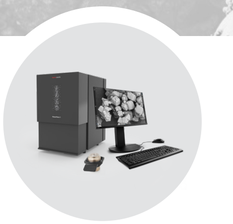
	Phenom Pure, Pro(X) G6 Desktop SEMs	Phenom XL G2 Desktop SEM	Axia ChemiSEM System	Prisma E SEM	Phenom Pharos G2 Desktop SEM	Quattro ESEM	Apreo ChemiSEM System	Verios 5 XHR SEM
Instruments								
Source type	Cerium hexaboride (CeB_6)		Tungsten (W)		Schottky field emission (FEG)			
Maximum resolution								0.8 nm
Sample size							122 mm	
Detector type	Secondary electrons (SE)	Backscattered electrons (BSE)	Low-vacuum SE	Cathodoluminescence *	Low-vacuum BSE *	STEM *	WetSTEM *	Gaseous SED
Environmental capabilities	High vacuum		Low vacuum (10-200 Pa)			Environmental (200-4000 Pa)		
Analytical capabilities	Elemental analysis *	Particle analysis *	Microstructural analysis	Correlative microscopy *	Scripting *	Fiber analysis *	Image interpretation *	

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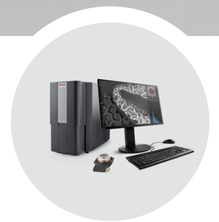
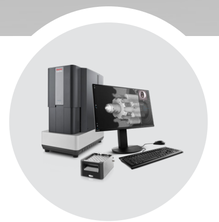
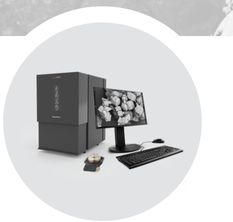
Instruments								
Source type	Cerium hexaboride (CeB_6)		Tungsten (W)		Schottky field emission (FEG)			
Maximum resolution								0.7 nm
Sample size							122 mm	
Detector type	Secondary electrons (SE)	Backscattered electrons (BSE)	Low-vacuum SE *	Cathodoluminescence *	Low-vacuum BSE *	STEM *	WetSTEM	Gaseous SED
Environmental capabilities	High vacuum		Low vacuum (10-500 Pa) *				Environmental	
Analytical capabilities	Elemental analysis	Particle analysis *	Microstructural analysis *	Correlative microscopy *	Scripting *	Fiber analysis *	Image interpretation *	

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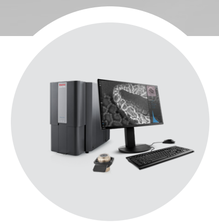
Instruments								
Source type	Cerium hexaboride (CeB_6)		Tungsten (W)		Schottky field emission (FEG)			
Maximum resolution								0.6 nm
Sample size						100 mm		
Detector type	Secondary electrons (SE)	Backscattered electrons (BSE)	Low-vacuum SE	Cathodoluminescence	Low-vacuum BSE	STEM *	WetSTEM	Gaseous SED
Environmental capabilities	High vacuum		Low vacuum			Environmental		
Analytical capabilities	Elemental analysis	Particle analysis *	Microstructural analysis	Correlative microscopy *	Scripting *	Fiber analysis *	Image interpretation *	

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